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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Obsolete
Core Processor	ARM7®
Core Size	16/32-Bit
Speed	60MHz
Connectivity	I²C, Microwire, SPI, SSI, SSP, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	47
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x10b; D/A 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-HVQFN (9x9)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc2132fhn64-557">https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc2132fhn64-557</a>

### 3.1 Ordering options

**Table 2. Ordering options**

Type number	Flash memory	RAM	ADC	DAC	Enhanced UARTs, ADC, Fast I/Os, and BOD	Temperature range
LPC2131FBD64/01	32 kB	8 kB	1	-	yes	–40 °C to +85 °C
LPC2132FBD64/01	64 kB	16 kB	1	1	yes	–40 °C to +85 °C
LPC2132FHN64/01	64 kB	16 kB	1	1	yes	–40 °C to +85 °C
LPC2134FBD64/01	128 kB	16 kB	2	1	yes	–40 °C to +85 °C
LPC2136FBD64/01	256 kB	32 kB	2	1	yes	–40 °C to +85 °C
LPC2138FBD64/01	512 kB	32 kB	2	1	yes	–40 °C to +85 °C
LPC2138FHN64/01	512 kB	32 kB	2	1	yes	–40 °C to +85 °C

## 5.2 Pin description

**Table 3. Pin description**

Symbol	Pin	Type	Description
P0.0 to P0.31		I/O	<b>Port 0:</b> Port 0 is a 32-bit I/O port with individual direction controls for each bit. Total of 31 pins of the Port 0 can be used as a general purpose bidirectional digital I/Os while P0.31 is output only pin. The operation of port 0 pins depends upon the pin function selected via the pin connect block. Pin P0.24 is not available.
P0.0/TXD0/ PWM1	19 <sup>[1]</sup>	O	<b>TXD0</b> — Transmitter output for UART0.
		O	<b>PWM1</b> — Pulse Width Modulator output 1.
P0.1/RXD0/ PWM3/EINT0	21 <sup>[2]</sup>	I	<b>RXD0</b> — Receiver input for UART0.
		O	<b>PWM3</b> — Pulse Width Modulator output 3.
		I	<b>EINT0</b> — External interrupt 0 input.
P0.2/SCL0/ CAP0.0	22 <sup>[3]</sup>	I/O	<b>SCL0</b> — I <sup>2</sup> C0 clock input/output. Open drain output (for I <sup>2</sup> C-bus compliance).
		I	<b>CAP0.0</b> — Capture input for Timer 0, channel 0.
P0.3/SDA0/ MAT0.0/EINT1	26 <sup>[3]</sup>	I/O	<b>SDA0</b> — I <sup>2</sup> C0 data input/output. Open drain output (for I <sup>2</sup> C-bus compliance).
		O	<b>MAT0.0</b> — Match output for Timer 0, channel 0.
		I	<b>EINT1</b> — External interrupt 1 input.
P0.4/SCK0/ CAP0.1/AD0.6	27 <sup>[4]</sup>	I/O	<b>SCK0</b> — Serial clock for SPI0. SPI clock output from master or input to slave.
		I	<b>CAP0.1</b> — Capture input for Timer 0, channel 1.
		I	<b>AD0.6</b> — ADC 0, input 6. This analog input is always connected to its pin.
P0.5/MISO0/ MAT0.1/AD0.7	29 <sup>[4]</sup>	I/O	<b>MISO0</b> — Master In Slave V <sub>DD</sub> = 3.6 V for SPI0. Data input to SPI master or data output from SPI slave.
		O	<b>MAT0.1</b> — Match output for Timer 0, channel 1.
		I	<b>AD0.7</b> — ADC 0, input 7. This analog input is always connected to its pin.
P0.6/MOSI0/ CAP0.2/AD1.0	30 <sup>[4]</sup>	I/O	<b>MOSI0</b> — Master Out Slave In for SPI0. Data output from SPI master or data input to SPI slave.
		I	<b>CAP0.2</b> — Capture input for Timer 0, channel 2.
		I	<b>AD1.0</b> — ADC 1, input 0. This analog input is always connected to its pin. Available in LPC2134/36/38 only.
P0.7/SSEL0/ PWM2/EINT2	31 <sup>[2]</sup>	I	<b>SSEL0</b> — Slave Select for SPI0. Selects the SPI interface as a slave.
		O	<b>PWM2</b> — Pulse Width Modulator output 2.
		I	<b>EINT2</b> — External interrupt 2 input.
P0.8/TXD1/ PWM4/AD1.1	33 <sup>[4]</sup>	O	<b>TXD1</b> — Transmitter output for UART1.
		O	<b>PWM4</b> — Pulse Width Modulator output 4.
		I	<b>AD1.1</b> — ADC 1, input 1. This analog input is always connected to its pin. Available in LPC2134/36/38 only.
P0.9/RXD1/ PWM6/EINT3	34 <sup>[2]</sup>	I	<b>RXD1</b> — Receiver input for UART1.
		O	<b>PWM6</b> — Pulse Width Modulator output 6.
		I	<b>EINT3</b> — External interrupt 3 input.
P0.10/RTS1/ CAP1.0/AD1.2	35 <sup>[4]</sup>	O	<b>RTS1</b> — Request to Send output for UART1. Available in LPC2134/36/38.
		I	<b>CAP1.0</b> — Capture input for Timer 1, channel 0.
		I	<b>AD1.2</b> — ADC 1, input 2. This analog input is always connected to its pin. Available in LPC2134/36/38 only.

Table 3. Pin description ...continued

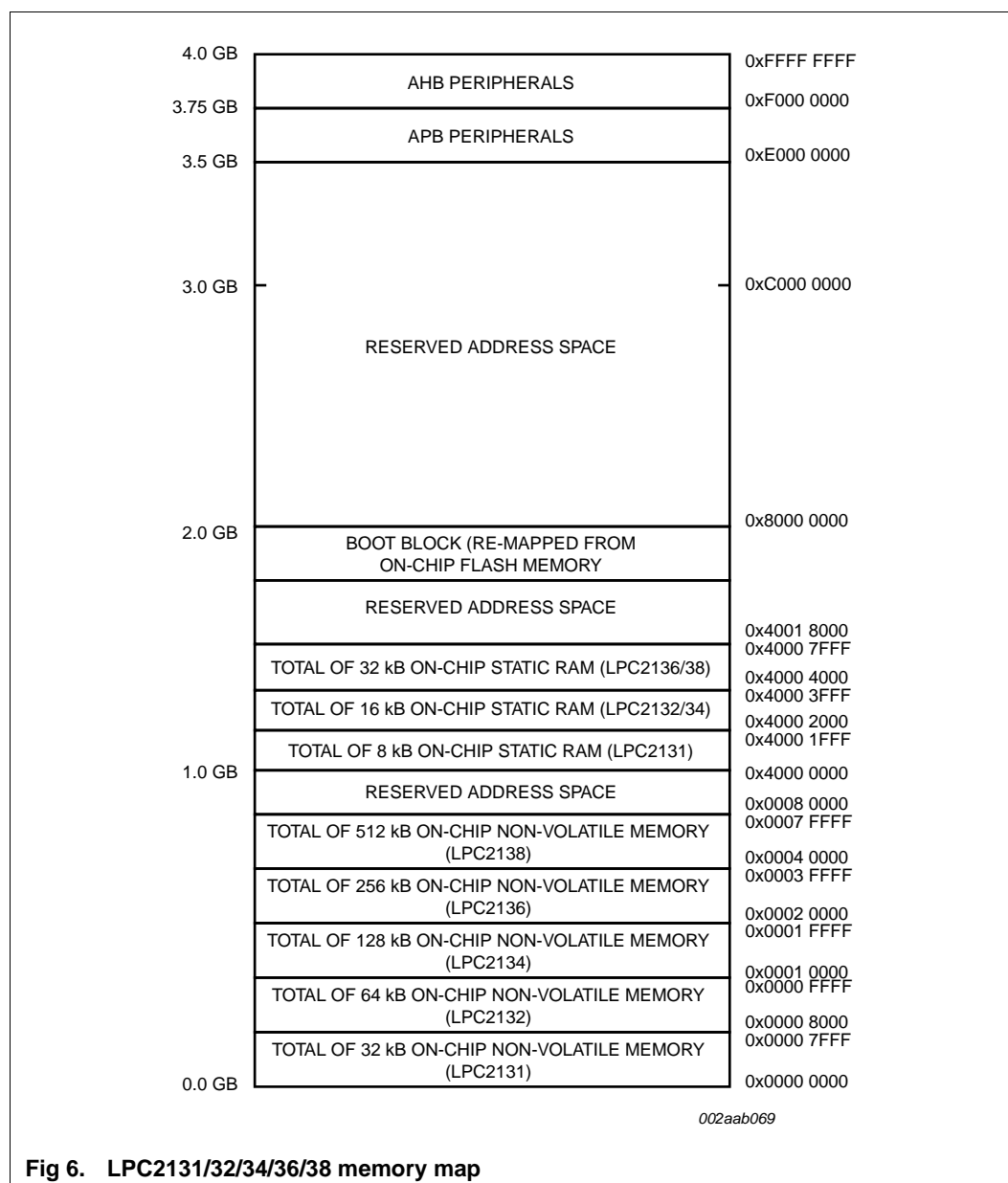
Symbol	Pin	Type	Description
P1.26/RTCK	24 <sup>[6]</sup>	I/O	<b>RTCK</b> — Returned Test Clock output. Extra signal added to the JTAG port. Assists debugger synchronization when processor frequency varies. Bidirectional pin with internal pull-up. LOW on RTCK while $\overline{\text{RESET}}$ is LOW enables pins P1.31:26 to operate as Debug port after reset.
P1.27/TDO	64 <sup>[6]</sup>	O	<b>TDO</b> — Test Data out for JTAG interface.
P1.28/TDI	60 <sup>[6]</sup>	I	<b>TDI</b> — Test Data in for JTAG interface.
P1.29/TCK	56 <sup>[6]</sup>	I	<b>TCK</b> — Test Clock for JTAG interface.
P1.30/TMS	52 <sup>[6]</sup>	I	<b>TMS</b> — Test Mode Select for JTAG interface.
P1.31/ $\overline{\text{TRST}}$	20 <sup>[6]</sup>	I	<b><math>\overline{\text{TRST}}</math></b> — Test Reset for JTAG interface.
$\overline{\text{RESET}}$	57 <sup>[7]</sup>	I	<b>External reset input:</b> A LOW on this pin resets the device, causing I/O ports and peripherals to take on their default states, and processor execution to begin at address 0. TTL with hysteresis, 5 V tolerant.
XTAL1	62 <sup>[8]</sup>	I	Input to the oscillator circuit and internal clock generator circuits.
XTAL2	61 <sup>[8]</sup>	O	Output from the oscillator amplifier.
RTCX1	3 <sup>[9]</sup>	I	Input to the RTC oscillator circuit.
RTCX2	5 <sup>[9]</sup>	O	Output from the RTC oscillator circuit.
V <sub>SS</sub>	6, 18, 25, 42, 50	I	<b>Ground:</b> 0 V reference.
V <sub>SSA</sub>	59	I	<b>Analog ground:</b> 0 V reference. This should nominally be the same voltage as V <sub>SS</sub> , but should be isolated to minimize noise and error.
V <sub>DD</sub>	23, 43, 51	I	<b>3.3 V power supply:</b> This is the power supply voltage for the core and I/O ports.
V <sub>DDA</sub>	7	I	<b>Analog 3.3 V power supply:</b> This should be nominally the same voltage as V <sub>DD</sub> but should be isolated to minimize noise and error. This voltage is used to power the on-chip PLL.
VREF	63	I	<b>ADC reference:</b> This should be nominally the same voltage as V <sub>DD</sub> but should be isolated to minimize noise and error. Level on this pin is used as a reference for A/D and D/A convertor(s).
VBAT	49	I	<b>RTC power supply:</b> 3.3 V on this pin supplies the power to the RTC.

- [1] 5 V tolerant pad providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control.
- [2] 5 V tolerant pad providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control. If configured for an input function, this pad utilizes built-in glitch filter that blocks pulses shorter than 3 ns.
- [3] Open drain 5 V tolerant digital I/O I<sup>2</sup>C-bus 400 kHz specification compatible pad. It requires external pull-up to provide an output functionality.
- [4] 5 V tolerant pad providing digital I/O (with TTL levels and hysteresis and 10 ns slew rate control) and analog input function. If configured for an input function, this pad utilizes built-in glitch filter that blocks pulses shorter than 3 ns. When configured as an ADC input, digital section of the pad is disabled.
- [5] 5 V tolerant pad providing digital I/O (with TTL levels and hysteresis and 10 ns slew rate control) and analog output function. When configured as the DAC output, digital section of the pad is disabled.
- [6] 5 V tolerant pad with built-in pull-up resistor providing digital I/O functions with TTL levels and hysteresis and 10 ns slew rate control. The pull-up resistor's value ranges from 60 k $\Omega$  to 300 k $\Omega$ .
- [7] 5 V tolerant pad providing digital input (with TTL levels and hysteresis) function only.
- [8] Pad provides special analog functionality.
- [9] When unused, the RTCX1 pin can be grounded or left floating. For lowest power leave it floating. The other RTC pin, RTCX2, should be left floating.

## 6.4 Memory map

The LPC2131/32/34/36/38 memory map incorporates several distinct regions, as shown in [Figure 6](#).

In addition, the CPU interrupt vectors may be re-mapped to allow them to reside in either flash memory (the default) or on-chip static RAM. This is described in [Section 6.18](#) “System control”.



**6.7.2 Fast I/O features available in LPC213x/01 only**

- Fast I/O registers are located on the ARM local bus for the fastest possible I/O timing.
- All GPIO registers are byte addressable.
- Entire port value can be written in one instruction.
- Mask registers allow single instruction to set or clear any number of bits in one port.

**6.8 10-bit ADC**

The LPC2131/32 contain one and the LPC2134/36/38 contain two ADCs. These converters are single 10-bit successive approximation ADCs with eight multiplexed channels.

**6.8.1 Features**

- Measurement range of 0 V to 3.3 V.
- Each converter capable of performing more than 400000 10-bit samples per second.
- Burst conversion mode for single or multiple inputs.
- Optional conversion on transition on input pin or Timer Match signal.
- Global Start command for both converters (LPC2134/36/38 only).

**6.8.2 ADC features available in LPC213x/01 only**

- Every analog input has a dedicated result register to reduce interrupt overhead.
- Every analog input can generate an interrupt once the conversion is completed.

**6.9 10-bit DAC**

This peripheral is available in the LPC2132/34/36/38 only. The DAC enables the LPC2132/34/36/38 to generate variable analog output.

**6.9.1 Features**

- 10-bit digital to analog converter.
- Buffered output.
- Power-down mode available.
- Selectable speed versus power.

**6.10 UARTs**

The LPC2131/32/34/36/38 each contain two UARTs. In addition to standard transmit and receive data lines, the LPC2134/36/38 UART1 also provides a full modem control handshake interface.

**6.10.1 Features**

- 16 B Receive and Transmit FIFOs.
- Register locations conform to 16C550 industry standard.
- Receiver FIFO trigger points at 1 B, 4 B, 8 B, and 14 B

- Built-in baud rate generator.
- Standard modem interface signals included on UART1. (LPC2134/36/38 only)
- The LPC2131/32/34/36/38 transmission FIFO control enables implementation of software (XON/XOFF) flow control on both UARTs and hardware (CTS/RTS) flow control on the LPC2134/36/38 UART1 only.

#### **6.10.2 UART features available in LPC213x/01 only**

- Fractional baud rate generator enables standard baud rates such as 115200 to be achieved with any crystal frequency above 2 MHz.
- Auto-bauding.
- Auto-CTS/RTS flow-control fully implemented in hardware (LPC2134/36/38 only).

### **6.11 I<sup>2</sup>C-bus serial I/O controller**

The LPC2131/32/34/36/38 each contain two I<sup>2</sup>C-bus controllers.

The I<sup>2</sup>C-bus is bidirectional, for inter-IC control using only two wires: a Serial Clock Line (SCL), and a Serial DATA line (SDA). Each device is recognized by a unique address and can operate as either a receiver-only device (e.g., an LCD driver or a transmitter with the capability to both receive and send information (such as memory)). Transmitters and/or receivers can operate in either master or slave mode, depending on whether the chip has to initiate a data transfer or is only addressed. The I<sup>2</sup>C-bus is a multi-master bus, it can be controlled by more than one bus master connected to it.

This I<sup>2</sup>C-bus implementation supports bit rates up to 400 kbit/s (Fast I<sup>2</sup>C).

#### **6.11.1 Features**

- Standard I<sup>2</sup>C compliant bus interface.
- Easy to configure as Master, Slave, or Master/Slave.
- Programmable clocks allow versatile rate control.
- Bidirectional data transfer between masters and slaves.
- Multi-master bus (no central master).
- Arbitration between simultaneously transmitting masters without corruption of serial data on the bus.
- Serial clock synchronization allows devices with different bit rates to communicate via one serial bus.
- Serial clock synchronization can be used as a handshake mechanism to suspend and resume serial transfer.
- The I<sup>2</sup>C-bus may be used for test and diagnostic purposes.

### **6.12 SPI serial I/O controller**

The LPC2131/32/34/36/38 each contain one SPI controller. The SPI is a full duplex serial interface, designed to be able to handle multiple masters and slaves connected to a given bus. Only a single master and a single slave can communicate on the interface during a given data transfer. During a data transfer the master always sends a byte of data to the slave, and the slave always sends a byte of data to the master.

The wake-up timer monitors the crystal oscillator as the means of checking whether it is safe to begin code execution. When power is applied to the chip, or some event caused the chip to exit Power-down mode, some time is required for the oscillator to produce a signal of sufficient amplitude to drive the clock logic. The amount of time depends on many factors, including the rate of  $V_{DD}$  ramp (in the case of power on), the type of crystal and its electrical characteristics (if a quartz crystal is used), as well as any other external circuitry (e.g. capacitors), and the characteristics of the oscillator itself under the existing ambient conditions.

#### 6.18.4 Brownout detector

The LPC2131/32/34/36/38 include 2-stage monitoring of the voltage on the  $V_{DD}$  pins. If this voltage falls below 2.9 V, the BOD asserts an interrupt signal to the Vectored Interrupt Controller. This signal can be enabled for interrupt; if not, software can monitor the signal by reading dedicated register.

The second stage of low-voltage detection asserts reset to inactivate the LPC2131/32/34/36/38 when the voltage on the  $V_{DD}$  pins falls below 2.6 V. This reset prevents alteration of the flash as operation of the various elements of the chip would otherwise become unreliable due to low voltage. The BOD circuit maintains this reset down below 1 V, at which point the POR circuitry maintains the overall reset.

Both the 2.9 V and 2.6 V thresholds include some hysteresis. In normal operation, this hysteresis allows the 2.9 V detection to reliably interrupt, or a regularly-executed event loop to sense the condition.

Features available only in LPC213x/01 parts include ability to put the BOD in power-down mode, turn it on or off and to control when the BOD will reset the LPC213x/01 microcontroller. This can be used to further reduce power consumption when a low power mode (such as Power Down) is invoked.

#### 6.18.5 Code security

This feature of the LPC2131/32/34/36/38 allow an application to control whether it can be debugged or protected from observation.

If after reset on-chip bootloader detects a valid checksum in flash and reads 0x8765 4321 from address 0x1FC in flash, debugging will be disabled and thus the code in flash will be protected from observation. Once debugging is disabled, it can be enabled only by performing a full chip erase using the ISP.

#### 6.18.6 External interrupt inputs

The LPC2131/32/34/36/38 include up to nine edge or level sensitive External Interrupt Inputs as selectable pin functions. When the pins are combined, external events can be processed as four independent interrupt signals. The External Interrupt Inputs can optionally be used to wake up the processor from Power-down mode.

#### 6.18.7 Memory Mapping Control

The Memory Mapping Control alters the mapping of the interrupt vectors that appear beginning at address 0x0000 0000. Vectors may be mapped to the bottom of the on-chip flash memory, or to the on-chip static RAM. This allows code running in different memory spaces to have control of the interrupts.



### 6.18.8 Power Control

The LPC2131/32/34/36/38 support two reduced power modes: Idle mode and Power-down mode.

In Idle mode, execution of instructions is suspended until either a reset or interrupt occurs. Peripheral functions continue operation during Idle mode and may generate interrupts to cause the processor to resume execution. Idle mode eliminates power used by the processor itself, memory systems and related controllers, and internal buses.

In Power-down mode, the oscillator is shut down and the chip receives no internal clocks. The processor state and registers, peripheral registers, and internal SRAM values are preserved throughout Power-down mode and the logic levels of chip output pins remain static. The Power-down mode can be terminated and normal operation resumed by either a reset or certain specific interrupts that are able to function without clocks. Since all dynamic operation of the chip is suspended, Power-down mode reduces chip power consumption to nearly zero.

Selecting an external 32 kHz clock instead of the PCLK as a clock-source for the on-chip RTC will enable the microcontroller to have the RTC active during Power-down mode. Power-down current is increased with RTC active. However, it is significantly lower than in Idle mode.

A Power Control for Peripherals feature allows individual peripherals to be turned off if they are not needed in the application, resulting in additional power savings.

### 6.18.9 APB bus

The APB divider determines the relationship between the processor clock (CCLK) and the clock used by peripheral devices (PCLK). The APB divider serves two purposes. The first is to provide peripherals with the desired PCLK via APB bus so that they can operate at the speed chosen for the ARM processor. In order to achieve this, the APB bus may be slowed down to  $\frac{1}{2}$  to  $\frac{1}{4}$  of the processor clock rate. Because the APB bus must work properly at power-up (and its timing cannot be altered if it does not work since the APB divider control registers reside on the APB bus), the default condition at reset is for the APB bus to run at  $\frac{1}{4}$  of the processor clock rate. The second purpose of the APB divider is to allow power savings when an application does not require any peripherals to run at the full processor rate. Because the APB divider is connected to the PLL output, the PLL remains active (if it was running) during Idle mode.

## 6.19 Emulation and debugging

The LPC2131/32/34/36/38 support emulation and debugging via a JTAG serial port. A trace port allows tracing program execution. Debugging and trace functions are multiplexed only with GPIOs on Port 1. This means that all communication, timer and interface peripherals residing on Port 0 are available during the development and debugging phase as they are when the application is run in the embedded system itself.

### 6.19.1 EmbeddedICE

Standard ARM EmbeddedICE logic provides on-chip debug support. The debugging of the target system requires a host computer running the debugger software and an EmbeddedICE protocol convertor. EmbeddedICE protocol convertor converts the Remote Debug Protocol commands to the JTAG data needed to access the ARM core.

The ARM core has a Debug Communication Channel function built-in. The debug communication channel allows a program running on the target to communicate with the host debugger or another separate host without stopping the program flow or even entering the debug state. The debug communication channel is accessed as a co-processor 14 by the program running on the ARM7TDMI-S core. The debug communication channel allows the JTAG port to be used for sending and receiving data without affecting the normal program flow. The debug communication channel data and control registers are mapped in to addresses in the EmbeddedICE logic.

### 6.19.2 Embedded trace

Since the LPC2131/32/34/36/38 have significant amounts of on-chip memory, it is not possible to determine how the processor core is operating simply by observing the external pins. The Embedded Trace Macrocell provides real-time trace capability for deeply embedded processor cores. It outputs information about processor execution to the trace port.

The ETM is connected directly to the ARM core and not to the main AMBA system bus. It compresses the trace information and exports it through a narrow trace port. An external trace port analyzer must capture the trace information under software debugger control. Instruction trace (or PC trace) shows the flow of execution of the processor and provides a list of all the instructions that were executed. Instruction trace is significantly compressed by only broadcasting branch addresses as well as a set of status signals that indicate the pipeline status on a cycle by cycle basis. Trace information generation can be controlled by selecting the trigger resource. Trigger resources include address comparators, counters and sequencers. Since trace information is compressed the software debugger requires a static image of the code being executed. Self-modifying code can not be traced because of this restriction.

### 6.19.3 RealMonitor

RealMonitor is a configurable software module, developed by ARM Inc., which enables real time debug. It is a lightweight debug monitor that runs in the background while users debug their foreground application. It communicates with the host using the DCC, which is present in the EmbeddedICE logic. The LPC2131/32/34/36/38 contain a specific configuration of RealMonitor software programmed into the on-chip flash memory.

## 7. Limiting values

**Table 5. Limiting values**

*In accordance with the Absolute Maximum Rating System (IEC 60134).*<sup>[1]</sup>

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DD</sub>	supply voltage (core and external rail)		−0.5	+3.6	V
V <sub>DDA</sub>	analog 3.3 V pad supply voltage		−0.5	+4.6	V
V <sub>i(VBAT)</sub>	input voltage on pin VBAT	for the RTC	−0.5	+4.6	V
V <sub>i(VREF)</sub>	input voltage on pin VREF		−0.5	+4.6	V
V <sub>IA</sub>	analog input voltage	on ADC related pins	−0.5	+5.1	V
V <sub>I</sub>	input voltage	5 V tolerant I/O pins; only valid when the V <sub>DD</sub> supply voltage is present	<sup>[2]</sup> −0.5	+6.0	V
		other I/O pins	<sup>[2][3]</sup> −0.5	V <sub>DD</sub> + 0.5	V
I <sub>DD</sub>	supply current	per supply pin	<sup>[4]</sup> -	100	mA
I <sub>SS</sub>	ground current	per ground pin	<sup>[4]</sup> -	100	mA
I <sub>sink</sub>	sink current	for I <sup>2</sup> C-bus; DC; T = 85 °C	-	20	mA
T <sub>stg</sub>	storage temperature		<sup>[5]</sup> −40	+125	°C
P <sub>tot(pack)</sub>	total power dissipation (per package)	based on package heat transfer, not device power consumption	-	1.5	W
V <sub>ESD</sub>	electrostatic discharge voltage	human body model	<sup>[6]</sup>		
		all pins	−4000	+4000	V

[1] The following applies to the Limiting values:

- a) This product includes circuitry specifically designed for the protection of its internal devices from the damaging effects of excessive static charge. Nonetheless, it is suggested that conventional precautions be taken to avoid applying greater than the rated maximum.
- b) Parameters are valid over operating temperature range unless otherwise specified. All voltages are with respect to V<sub>SS</sub> unless otherwise noted.

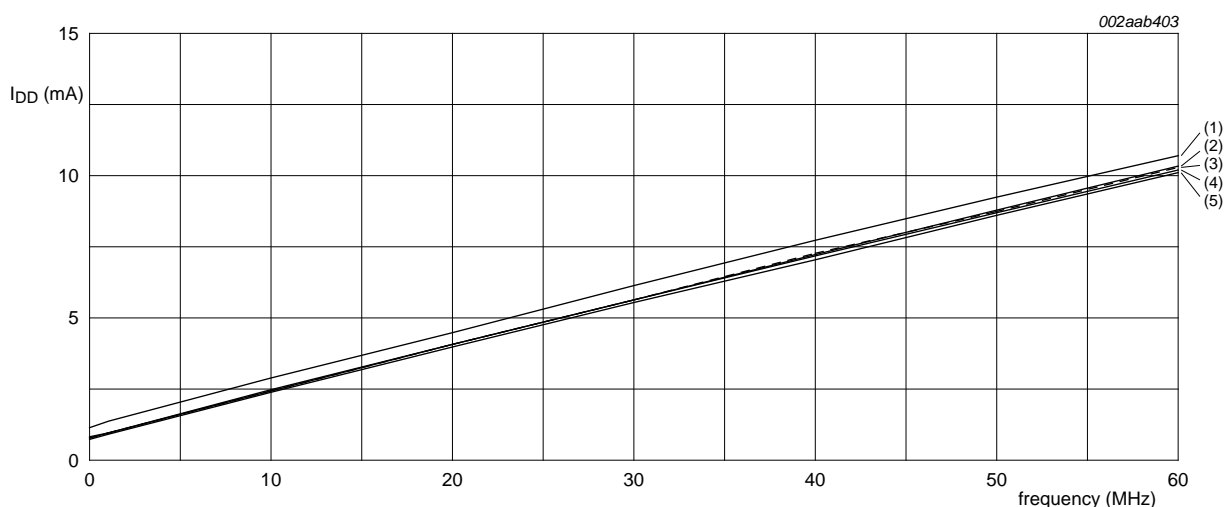
[2] Including voltage on outputs in 3-state mode.

[3] Not to exceed 4.6 V.

[4] The peak current is limited to 25 times the corresponding maximum current.

[5] Dependent on package type.

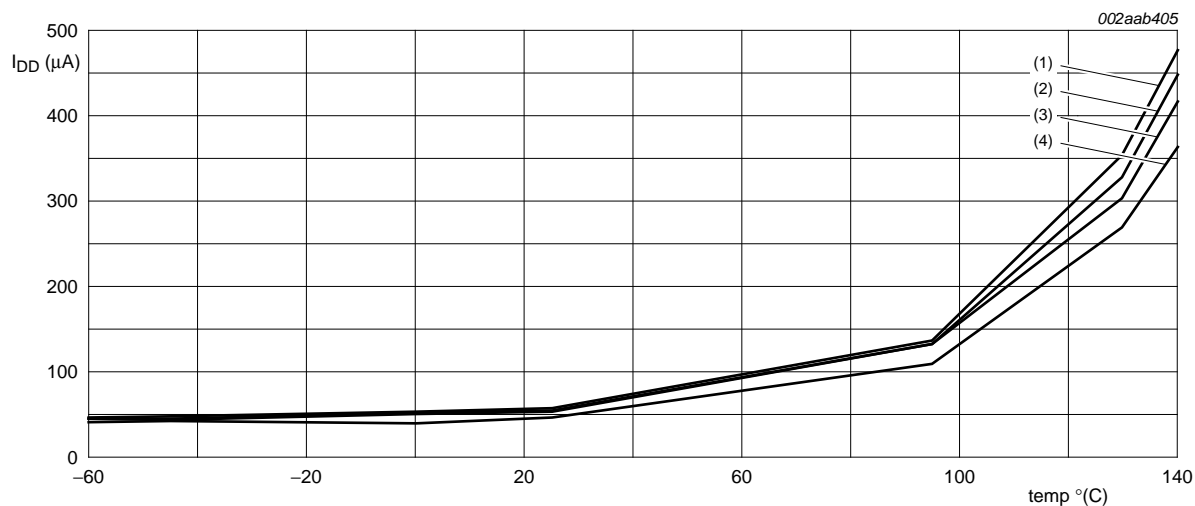
[6] Human body model: equivalent to discharging a 100 pF capacitor through a 1.5 kΩ series resistor.



Test conditions: Idle mode entered executing code from flash; all peripherals are enabled in PCONP register;  
PCLK = CCLK/4.

- (1)  $V_{DD} = 3.6$  V at 140 °C (max)
- (2)  $V_{DD} = 3.6$  V at -60 °C
- (3)  $V_{DD} = 3.6$  V at 25 °C
- (4)  $V_{DD} = 3.3$  V at 25 °C (typical)
- (5)  $V_{DD} = 3.3$  V at 95 °C (typical)

**Fig 9.  $I_{DD}$  idle measured at different frequencies (CCLK) and temperatures**



Test conditions: Power-down mode entered executing code from flash; all peripherals are enabled in PCONP register.

- (1)  $V_{DD} = 3.6$  V
- (2)  $V_{DD} = 3.3$  V (max)
- (3)  $V_{DD} = 3.0$  V
- (4)  $V_{DD} = 3.3$  V (typical)

**Fig 10.  $I_{DD(pd)}$  measured at different temperatures**

## 10. ADC electrical characteristics

**Table 8. ADC static characteristics**

$V_{DDA} = 2.5\text{ V to }3.6\text{ V}$ ;  $T_{amb} = -40\text{ }^{\circ}\text{C to }+85\text{ }^{\circ}\text{C}$  unless otherwise specified; ADC frequency 4.5 MHz.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IA}$	analog input voltage		0	-	$V_{DDA}$	V
$C_{ia}$	analog input capacitance		-	-	1	pF
$E_D$	differential linearity error	[1][2][3]	-	-	$\pm 1$	LSB
$E_{L(adj)}$	integral non-linearity	[1][4]	-	-	$\pm 2$	LSB
$E_O$	offset error	[1][5]	-	-	$\pm 3$	LSB
$E_G$	gain error	[1][6]	-	-	$\pm 0.5$	%
$E_T$	absolute error	[1][7]	-	-	$\pm 4$	LSB
$R_{vsi}$	voltage source interface resistance	[8]	-	-	40	k $\Omega$

[1] Conditions:  $V_{SSA} = 0\text{ V}$ ,  $V_{DDA} = 3.3\text{ V}$ .

[2] The ADC is monotonic, there are no missing codes.

[3] The differential linearity error ( $E_D$ ) is the difference between the actual step width and the ideal step width. See [Figure 11](#).

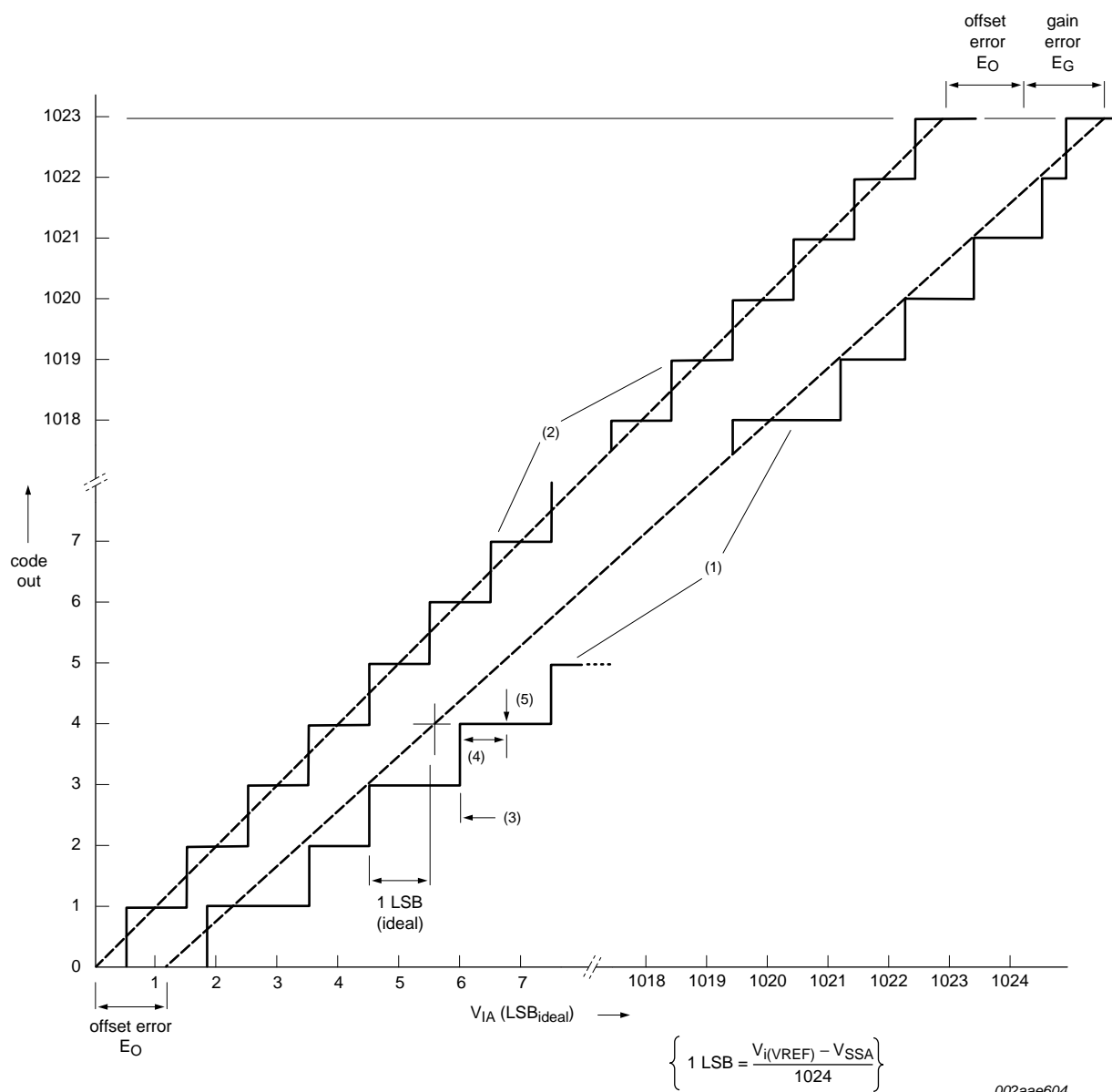
[4] The integral non-linearity ( $E_{L(adj)}$ ) is the peak difference between the center of the steps of the actual and the ideal transfer curve after appropriate adjustment of gain and offset errors. See [Figure 11](#).

[5] The offset error ( $E_O$ ) is the absolute difference between the straight line which fits the actual curve and the straight line which fits the ideal curve. See [Figure 11](#).

[6] The gain error ( $E_G$ ) is the relative difference in percent between the straight line fitting the actual transfer curve after removing offset error, and the straight line which fits the ideal transfer curve. See [Figure 11](#).

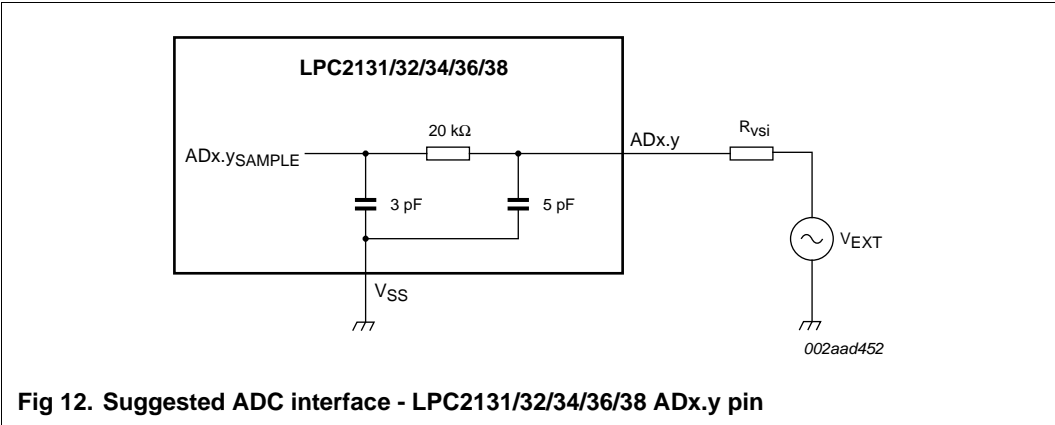
[7] The absolute error ( $E_T$ ) is the maximum difference between the center of the steps of the actual transfer curve of the non-calibrated ADC and the ideal transfer curve. See [Figure 11](#).

[8] See [Figure 11](#).



- (1) Example of an actual transfer curve.
- (2) The ideal transfer curve.
- (3) Differential linearity error ( $E_D$ ).
- (4) Integral non-linearity ( $E_{L(adj)}$ ).
- (5) Center of a step of the actual transfer curve.

**Fig 11. ADC characteristics**



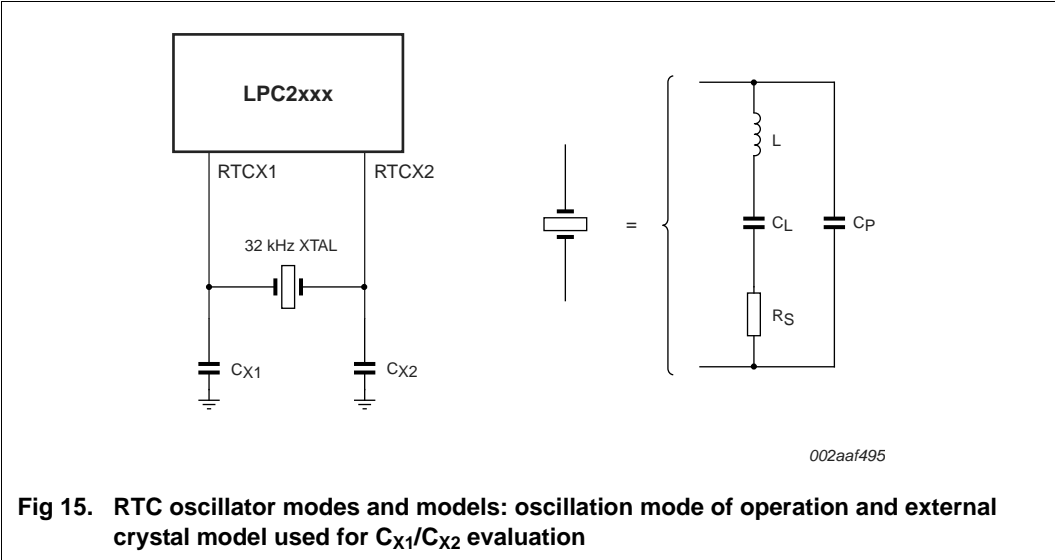
## 11. DAC electrical characteristics

**Table 9. DAC electrical characteristics***V<sub>DDA</sub> = 3.0 V to 3.6 V; T<sub>amb</sub> = -40 °C to +85 °C unless otherwise specified*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
E <sub>D</sub>	differential linearity error		-	±1	-	LSB
E <sub>L(adj)</sub>	integral non-linearity		-	±1.5	-	LSB
E <sub>O</sub>	offset error		-	0.6	-	%
E <sub>G</sub>	gain error		-	0.6	-	%
C <sub>L</sub>	load capacitance		-	200	-	pF
R <sub>L</sub>	load resistance		1	-	-	kΩ



12.2 RTC 32 kHz oscillator component selection



The RTC external oscillator circuit is shown in [Figure 15](#). Since the feedback resistance is integrated on chip, only a crystal, the capacitances  $C_{X1}$  and  $C_{X2}$  need to be connected externally to the microcontroller.

[Table 12](#) gives the crystal parameters that should be used.  $C_L$  is the typical load capacitance of the crystal and is usually specified by the crystal manufacturer. The actual  $C_L$  influences oscillation frequency. When using a crystal that is manufactured for a different load capacitance, the circuit will oscillate at a slightly different frequency (depending on the quality of the crystal) compared to the specified one. Therefore for an accurate time reference it is advised to use the load capacitors as specified in [Table 12](#) that belong to a specific  $C_L$ . The value of external capacitances  $C_{X1}$  and  $C_{X2}$  specified in this table are calculated from the internal parasitic capacitances and the  $C_L$ . Parasitics from PCB and package are not taken into account.

Table 12. Recommended values for the RTC external 32 kHz oscillator  $C_{X1}/C_{X2}$  components

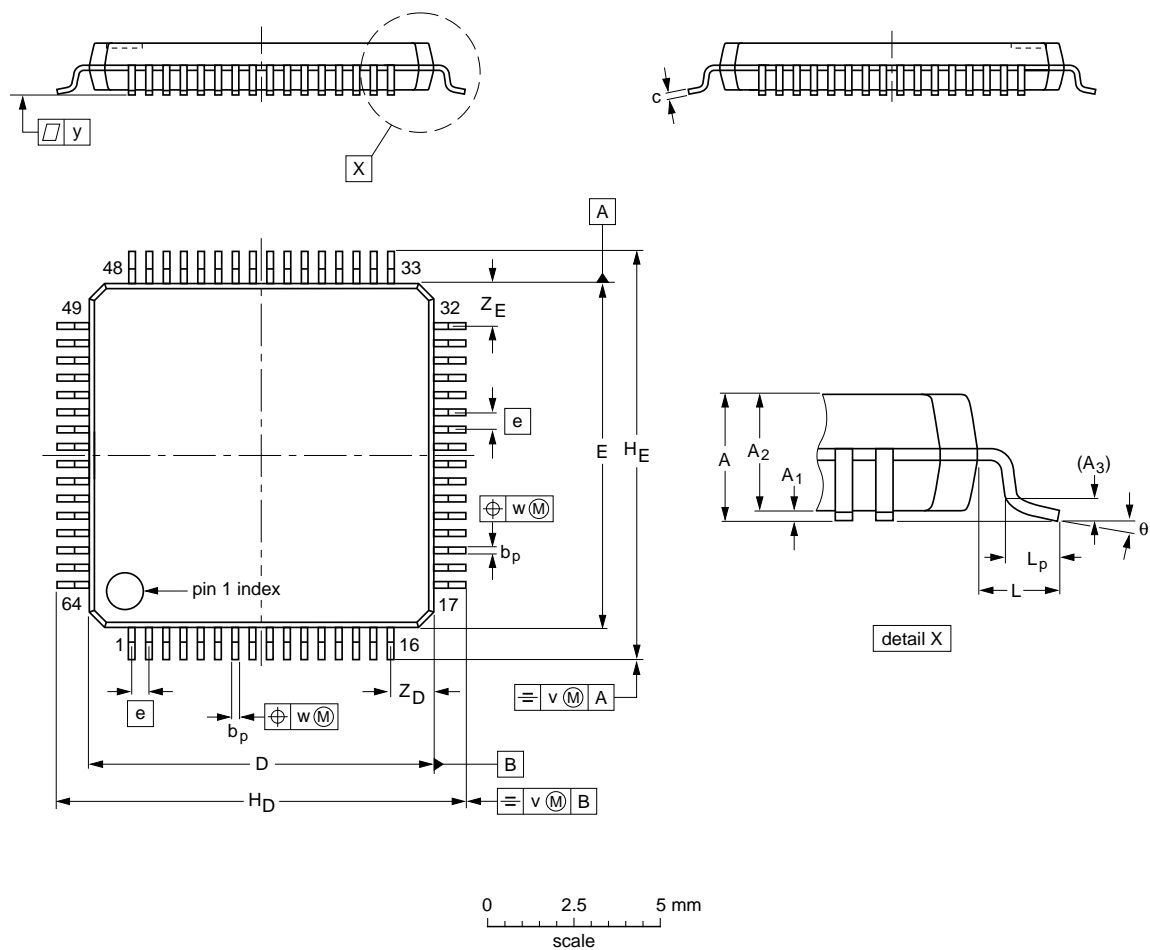
Crystal load capacitance $C_L$	Maximum crystal series resistance $R_S$	External load capacitors $C_{X1}/C_{X2}$
11 pF	< 100 k $\Omega$	18 pF, 18 pF
13 pF	< 100 k $\Omega$	22 pF, 22 pF
15 pF	< 100 k $\Omega$	27 pF, 27 pF

12.3 XTAL and RTCX Printed Circuit Board (PCB) layout guidelines

The crystal should be connected on the PCB as close as possible to the oscillator input and output pins of the chip. Take care that the load capacitors  $C_{X1}$ ,  $C_{X2}$ , and  $C_{X3}$  in case of third overtone crystal usage have a common ground plane. The external components must also be connected to the ground plane. Loops must be made as small as possible in order to keep the noise coupled in via the PCB as small as possible. Also parasitics should stay as small as possible. Values of  $C_{X1}$  and  $C_{X2}$  should be chosen smaller accordingly to the increase in parasitics of the PCB layout.

13. Package outline

LQFP64: plastic low profile quad flat package; 64 leads; body 10 x 10 x 1.4 mmSOT314-2



DIMENSIONS (mm are the original dimensions)

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b <sub>P</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	H <sub>D</sub>	H <sub>E</sub>	L	L <sub>P</sub>	v	w	y	Z <sub>D</sub> <sup>(1)</sup>	Z <sub>E</sub> <sup>(1)</sup>	θ
mm	1.6	0.20 0.05	1.45 1.35	0.25	0.27 0.17	0.18 0.12	10.1 9.9	10.1 9.9	0.5	12.15 11.85	12.15 11.85	1	0.75 0.45	0.2	0.12	0.1	1.45 1.05	1.45 1.05	7° 0°

**Note**  
1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT314-2	136E10	MS-026				00-01-19- 03-02-25

Fig 16. Package outline SOT314-2 (LQFP64)

HVQFN64: plastic thermal enhanced very thin quad flat package; no leads; 64 terminals;  
body 9 x 9 x 0.85 mm

SOT804-2

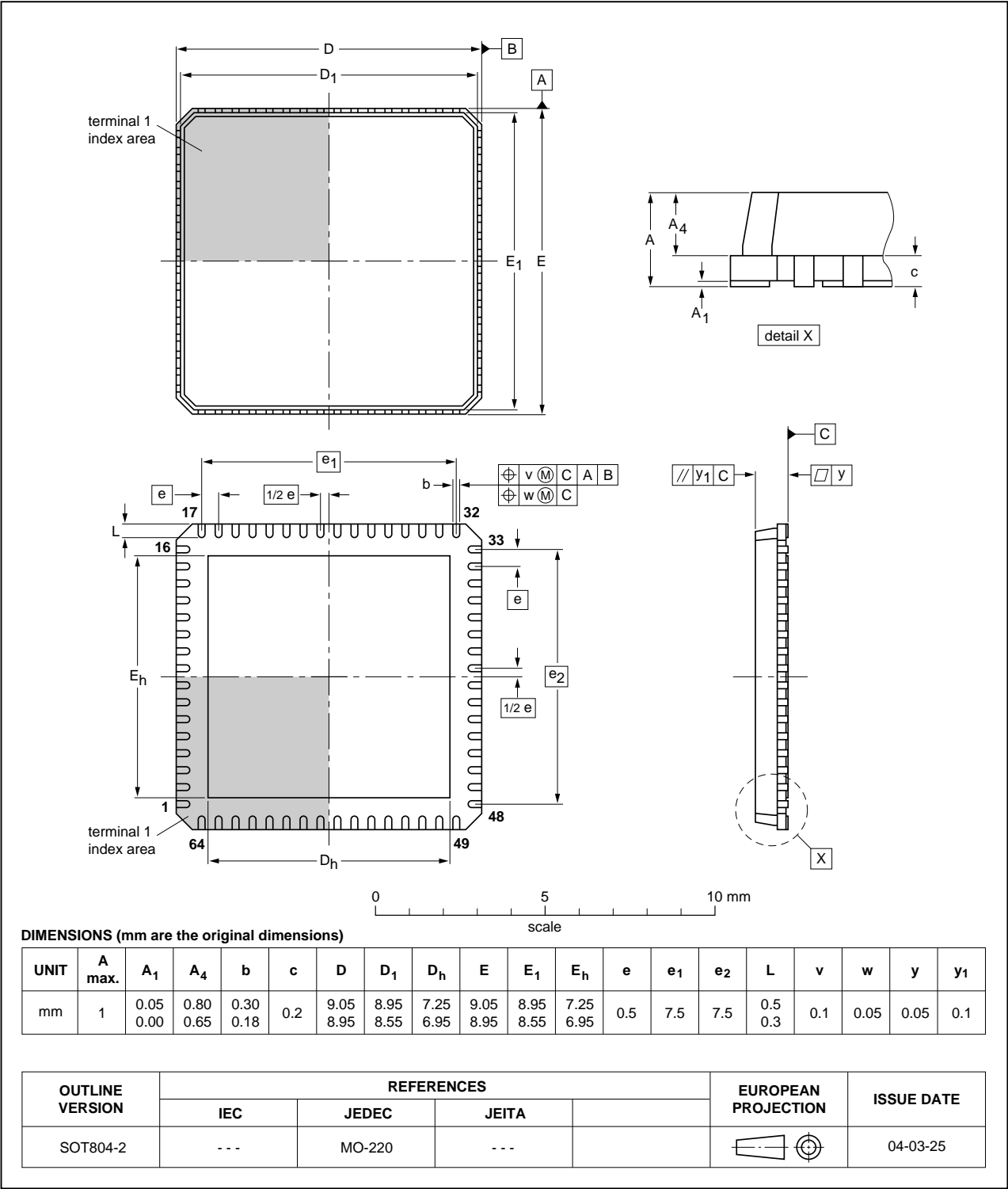


Fig 17. Package outline SOT804-2 (HVQFN64)

## 14. Abbreviations

Table 13. Acronym list

Acronym	Description
A/D	Analog-to-Digital
ADC	Analog-to-Digital Converter
AHB	Advanced High-performance Bus
AMBA	Advanced Microcontroller Bus Architecture
APB	Advanced Peripheral Bus
BOD	BrownOut Detection
CPU	Central Processing Unit
DAC	Digital-to-Analog Converter
DCC	Debug Communications Channel
ETM	Embedded Trace Macrocell
FIFO	First In, First Out
GPIO	General Purpose Input/Output
JTAG	Joint Test Action Group
LSB	Least Significant Bit
PLL	Phase-Locked Loop
POR	Power-On Reset
PWM	Pulse Width Modulator
RAM	Random Access Memory
SPI	Serial Peripheral Interface
SRAM	Static Random Access Memory
SSP	Synchronous Serial Port
UART	Universal Asynchronous Receiver/Transmitter

## 15. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
LPC2131_32_34_36_38 v.5.1	20110729	Product data sheet	-	LPC2131_32_34_36_38 v.5
Modifications:	<ul style="list-style-type: none"> <li>Parameter <math>I_{\text{sink}}</math> added in Table 5 "Limiting values".</li> <li>Table 6 "Static characteristics": Updated crystal oscillator specs</li> </ul>			
LPC2131_32_34_36_38 v.5	20110202	Product data sheet	-	LPC2131_32_34_36_38 v.4
Modifications:	<ul style="list-style-type: none"> <li>Table 3 "Pin description": Added Table note [9] to RTCX1 and RTCX2 pins.</li> <li>Table 6 "Static characteristics", I<sup>2</sup>C-bus pins: Changed typical hysteresis voltage from <math>0.5V_{\text{DD}}</math> to <math>0.05V_{\text{DD}}</math>.</li> <li>Table 6 "Static characteristics": Removed table note for <math>V_{\text{IH}}</math> and <math>V_{\text{IL}}</math>.</li> <li>Changed all occurrences of VPB to APB.</li> <li>Table 6 "Static characteristics": Added Table note [6] to <math>V_{\text{I}}</math>.</li> <li>Table 6 "Static characteristics", Standard port pins, RESET, RTCK: <math>V_{\text{hys}}</math> hysteresis voltage (0.4 V) moved from typical to minimum.</li> <li>Table 6 "Static characteristics": Changed <math>V_{\text{I(VREF)}}</math> minimum voltage from 3.0 V to 2.5 V.</li> <li>Table 6 "Static characteristics": Updated min, typical and max values for oscillator pins <math>V_{\text{I(XTAL1)}}</math>, <math>V_{\text{O(XTAL2)}}</math>, <math>V_{\text{I(RTCX1)}}</math>, and <math>V_{\text{O(RTCX2)}}</math>.</li> <li>Added Section 11 "DAC electrical characteristics".</li> <li>Added Section 12 "Application information".</li> </ul>			
LPC2131_32_34_36_38 v.4	20071016	Product data sheet	-	LPC2131_32_34_36_38 v.3
LPC2131_32_34_36_38 v.3	20060921	Product data sheet	-	LPC2131_32_34_36_38 v.2
LPC2131_32_34_36_38 v.2	20050318	Preliminary data sheet	-	LPC2131_2132_2138 v.1
LPC2131_2132_2138 v.1	20041118	Preliminary data sheet	-	-